## Applicant(s)/Patent Under Application/Control No. Reexamination 10/661,116 PUTNAM ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Arnel C. Lavarias 2872 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-Α В US-С US-D US-US-Ε F US-G US-Н US-I US-US-J Κ US-US-L М US-**FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY JP11119029A1 Ν 04-1999 Japan Terao G02B006/00 0 Ρ Q R S T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U NONE W

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